

## Supporting information

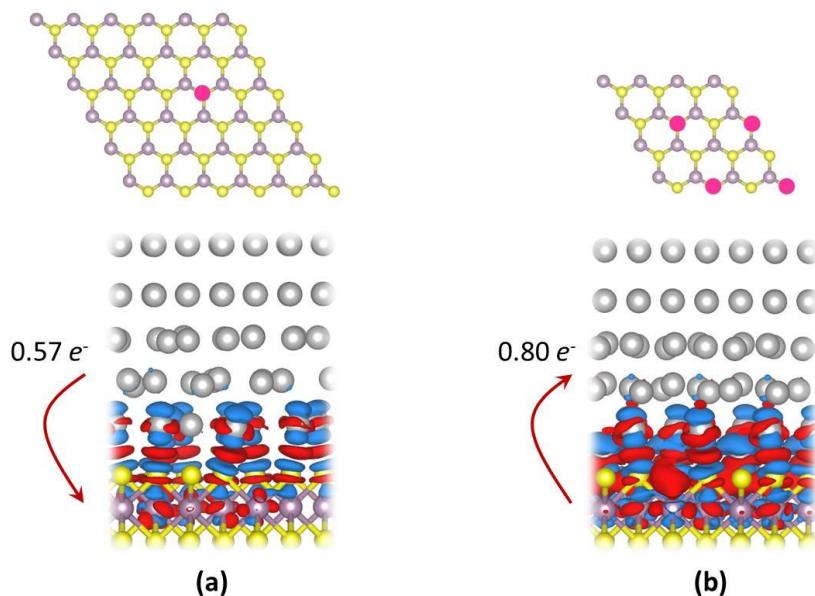
### Electrical Doping Effect of Vacancies in Monolayer MoS<sub>2</sub>

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**Figure S1: Top view of (a) V<sub>1s</sub> within a 6×6 unit cell and (b) evenly distributed V<sub>4s</sub> within a 4×4 unit cell, with the electron density difference map associated with the interaction between Au and MoS<sub>2</sub> with each Vs configuration shown directly below. Blue and red zones correspond to electron reduction and accumulation areas, respectively. Grey, yellow and purple spheres represent Au, S, Mo and atoms. The pink dots represent the Vs position. The arrow and the number show the charge transfer direction and amount predicted by Bader charge. Note the different configuration here results in the degree of charge transfer in (b) being lower than that for Fig. 1(e) and Fig. 5(e), despite having the same Vs density.**

**Table S1. Charge transfer amount (per surface Au atom, in  $e^-$ ) calculated with different K-points mesh. A positive charge transfer amount corresponds to the charge flow from MoS<sub>2</sub> to Au, suggesting an *n*-type contact, and a negative charge transfer denotes an opposite direction, indicating a *p*-type contact.**

| vacancy type | 2×2×1  | 4×4×1  | 6×6×1  |
|--------------|--------|--------|--------|
| 1S           | -0.018 | -0.021 | -0.022 |
| 4S           | 0.062  | 0.056  | 0.055  |

**Table S2. Charge transfer amount (total and per surface Au atom, in  $e^-$ ) calculated for different vacancy types. A positive charge transfer amount corresponds to the charge flow from MoS<sub>2</sub> to Au, suggesting an *n*-type contact, and a negative charge transfer denotes an opposite direction, indicating a *p*-type contact.**

| systems                              | charge transfer amount (in $e^-$ ) |                     |
|--------------------------------------|------------------------------------|---------------------|
|                                      | total                              | per surface Au atom |
| pristine                             | -0.060                             | ~0.00               |
| V <sub>1S</sub> (6×6 unit cell)      | -0.57                              | -0.016              |
| V <sub>1S</sub>                      | 0.28                               | -0.018              |
| V <sub>2S</sub>                      | 0.31                               | 0.019               |
| V <sub>3S</sub>                      | 0.72                               | 0.045               |
| V <sub>4S</sub>                      | 0.99                               | 0.062               |
| V <sub>4S</sub> (evenly distributed) | 0.80                               | 0.050               |
| V <sub>1Mo</sub>                     | -0.52                              | -0.033              |
| V <sub>2Mo</sub>                     | -0.56                              | -0.035              |

**I-V curve simulation:** In the main text, we simulated the junction current of Au-MoS<sub>2</sub> contact using the Schottky-Mott model and the thermionic emission model. Here, we explain these models in more details and explain how we obtain the simulated curves.

By the Schottky-Mott model, the pristine *n*-type Schottky barrier height  $\phi_{b,n}$  is given by:

$$\phi_{b,n} = \Phi_M - \chi_S = 1 \text{ eV}$$

where  $\Phi_M$  is the metal work function of Au ( $\sim 5.1$  eV) and  $\chi_S$  is the electron affinity of MoS<sub>2</sub> ( $\sim 4.1$  eV).

The *p*-type Schottky barrier height  $\phi_{b,p}$  can be estimated using the band gap of monolayer MoS<sub>2</sub> (1.8 eV).

$$\phi_{b,p} = E_g - \phi_{b,n} = 0.8 \text{ eV}$$

For simulating the junction current, we used the thermionic emission model which is given by:

$$J = \left[ A^{**} T^2 \exp\left(\frac{-q\phi_b}{kT}\right) \right] \left[ \exp\left(\frac{q(V - IR_s)}{nkT}\right) - 1 \right]$$

where  $J$  (Acm<sup>-2</sup>) is the current density of the device ,  $A^{**}$  is the effective Richardson constant of MoS<sub>2</sub> ( $= 44.8$  Acm<sup>-2</sup>K<sup>-1</sup>),  $q$  is the electronic charge ( $= 1.602 \times 10^{-19}$  C),  $T$  (K) is the absolute temperature,  $k$  is the Boltzmann constant ( $= 8.617 \times 10^{-5}$  eVK<sup>-1</sup>), ideality factor  $n = 1$  (ideal diode),  $R_s$  is the series resistance (assumed to be 25 Ω).

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